

| | | |
|---|--|---|
| Form PTO-1449 (modified) List of Patents and Publications For Applicant's Information Disclosure Statement (Use several sheets if necessary) MAR 31 2003 | ATTY. DKT. NO. 5589-02305 <i>W/ Komrad et al</i> APPLICANT: <i>W/ Komrad et al</i> | SERIAL NO. 09/957,468 GROUP: 2852 <i>2877</i> |
| | FILING DATE: September 20, 2001 | |

U.S. PATENT DOCUMENTS

| EXAM. INITIALS | REF. DES. | DOCUMENT NUMBER | DATE | NAME | CLASS | SUB CLASS | FILING DATE IF APPROPRIATE |
|-------------------|--------------|-----------------|---------|-----------------|----------|--------------|-------------------------------|
| <i>HP</i> | D28 | 2002/0149782 | 10/2002 | Raymond | <i>—</i> | <i>—</i> | |
| <i>HP</i> | D29 | 2002/0158193 | 10/2002 | Sezginer et al. | <i>—</i> | <i>—</i> | |
| <i>HP</i> | D30 | 2002/0192577 | 12/2002 | Fay et al. | <i>—</i> | <i>—</i> | |
| | | | | | | | |
| | | | | | | | |

FOREIGN PATENT DOCUMENTS

| EXAM. INITIALS | REF. DES. | DOCUMENT NUMBER | DATE | COUNTRY | CLASS | SUB CLASS | TRANSLATION YES/NO |
|-------------------|--------------|-----------------|--------|---------|----------|--------------|-----------------------|
| <i>HP</i> | D31 | 02/15238 | 2/2002 | WO | <i>—</i> | <i>—</i> | |
| <i>HP</i> | D32 | 02/25723 | 3/2002 | WO | <i>—</i> | <i>—</i> | |
| <i>HP</i> | D33 | 02/069390 | 9/2002 | WO | <i>—</i> | <i>—</i> | |
| | | | | | | | |

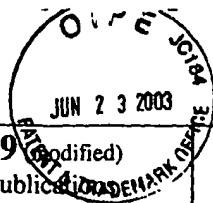
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

| | | |
|-----------|-----|--|
| <i>HP</i> | D34 | McNeil et al., "Scatterometry Applied to Microelectronics Processing," Microlithography World, November/December 1992, pp. 16-22. |
| <i>HP</i> | D35 | Raymond et al., "Metrology of subwavelength photoresist gratings using optical scatterometry," J. Vac. Sci. Technol. B 13(4), Jul/Aug 1995, pp. 1484-1495. |
| <i>HP</i> | D36 | Wittekoek et al., "In-process Image Detecting Technique for Determination of Overlay, and Image Quality for ASM-L Wafer Stepper," SPIE Vol. 1674 Optical/Laser Microlithography V (1992), pp. 594-608. |
| | | |
| | | |
| | | |
| | | |
| | | |
| | | |
| | | |
| | | |
| | | |
| | | |
| | | |
| | | |
| | | |

EXAMINER: *HP*

DATE CONSIDERED: *7/28/04*

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the patent owner.



| | | |
|---|---|--|
| Form PTO-1449 (modified) List of Patents and Publications For Applicant's Information Disclosure Statement (Use several sheets if necessary) | ATTY. DKT. NO. 5589-02305 APPLICANT: <i>Levy et al.</i> <i>McDonahed</i> FILING DATE: September 20, 2001 | SERIAL NO. 09/957,468 GROUP: 2862 2877 |
|---|---|--|

U.S. PATENT DOCUMENTS

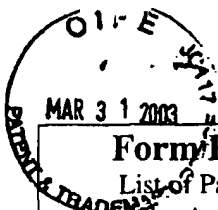
| EXAM. INITIALS | REF. DES. | DOCUMENT NUMBER | DATE | NAME | CLASS | SUB CLASS | FILING DATE IF APPROPRIATE |
|-------------------|--------------|-----------------|---------|-------------------|-------|--------------|-------------------------------|
| <i>HP</i> | E1 | 5,438,413 | 8/1995 | Mazor et al. | | | |
| <i>HP</i> | E2 | 5,574,278 | 11/1996 | Poirier | | | |
| <i>A</i> | E3 | 5,703,692 | 12/1997 | McNeil et al. | | | |
| | E4 | 5,798,529 | 8/1998 | Wagner | | | |
| | E5 | 5,923,423 | 7/1999 | Sawatari et al. | | | |
| | E6 | 5,963,314 | 10/1999 | Worster et al. | | | |
| | E7 | 6,052,188 | 4/2000 | Fluckiger et al. | | | |
| | E8 | 6,097,205 | 8/2000 | Lieberman et al. | | | |
| | E9 | 6,157,032 | 12/2000 | Into | | | |
| | E10 | 6,166,801 | 12/2000 | Dishon et al. | | | |
| | E11 | 6,174,743 | 1/2001 | Pangrle et al. | | | |
| | E12 | 6,175,421 | 1/2001 | Fuchs et al. | | | |
| | E13 | 6,188,478 | 2/2001 | Fuchs et al. | | | |
| | E14 | 6,191,846 | 2/2001 | Opsal et al. | | | |
| | E15 | 6,250,143 | 6/2001 | Bindell et al. | | | |
| | E16 | 6,258,610 | 7/2001 | Blatchford et al. | | | |
| | E17 | 6,266,144 | 7/2001 | Li | | | |
| | E18 | 6,320,666 | 11/2001 | Opsal et al. | | | |
| | E19 | US 2001/0052257 | 12/2001 | Magerle | | | |
| | E20 | US 2002/0017619 | 2/2002 | Hirose et al. | | | |
| | E21 | 6,383,824 | 5/2002 | Lensing | | | |
| | E22 | 6,408,048 | 6/2002 | Opsal et al. | | | |
| <i>J</i> | E23 | 6,451,621 | 9/2002 | Rangarajan et al. | | | |
| <i>HP</i> | E24 | 6,452,685 | 9/2002 | Opsal et al. | | | |
| <i>HP</i> | E25 | 6,462,817 | 10/2002 | Strocchia-Rivera | | | |
| | | | | | | | |

EXAMINER:

DATE CONSIDERED:

7/28/04

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the patent owner.



| | | |
|---|---|---|
| Form PTO-1449 (modified) List of Patents and Publications For Applicant's Information Disclosure Statement (Use several sheets if necessary) | ATTY. DKT. NO. 5589-02305 <i>Nikornukhal et al</i> APPLICANT: <i>Levy et al.</i> FILING DATE: September 20, 2001 | SERIAL NO. 09/957,468 GROUP: 287 2877 |
|---|---|---|

U.S. PATENT DOCUMENTS

| EXAM. INITIALS | REF. DES. | DOCUMENT NUMBER | DATE | NAME | CLASS | SUB CLASS | FILING DATE IF APPROPRIATE |
|-------------------|--------------|-----------------|---------|---------------------|-------|--------------|-------------------------------|
| <i>HP</i> | D1 | 4631416 | 12/1986 | Trutna, Jr. | ↑ | ↑ | |
| <i>HP</i> | D2 | 5114235 | 5/1992 | Suda et al. | | | |
| ↑ | D3 | 5182455 | 1/1993 | Muraki | | | |
| | D4 | 5182610 | 1/1993 | Shibata | | | |
| | D5 | 5189494 | 2/1993 | Muraki | | | |
| | D6 | 5316984 | 5/1994 | Leourx | | | |
| | D7 | 5327221 | 7/1994 | Saitoh et al. | | | |
| | D8 | 5340992 | 8/1994 | Matsugu et al. | | | |
| | D9 | 5414514 | 5/1995 | Smith et al. | | | |
| | D10 | 5666196 | 9/1997 | Ishii et al. | | | |
| | D11 | 5783342 | 7/1998 | Yamashita et al. | | | |
| | D12 | 5801390 | 9/1998 | Shiraishi | | | |
| | D13 | 6046094 | 4/2000 | Jost et al. | | | |
| | D14 | 6077756 | 6/2000 | Lin et al. | | | |
| | D15 | 6079256 | 6/2000 | Bareket | | | |
| | D16 | 6128089 | 10/2000 | Ausschnitt et al. | | | |
| | D17 | 6153886 | 11/2000 | Hagiwara et al. | | | |
| | D18 | 6177330 | 1/2001 | Yasuda | | | |
| | D19 | 6255189 | 7/2001 | Muller et al. | | | |
| | D20 | 6301011 | 10/2001 | Fung et al. | | | |
| | D21 | 6388253 | 5/2002 | Su | | | |
| | D22 | 6421124 | 7/2002 | Matsumoto et al. | | | |
| | D23 | 6462818 | 10/2002 | Bareket | | | |
| | D24 | 6476920 | 11/2002 | Scheiner et al. | | | |
| | D25 | 6486492 | 11/2002 | Su | | | |
| <i>HP</i> | D26 | 6486954 | 11/2002 | Mieher et al. | | | |
| <i>HP</i> | D27 | 2002/0018217 | 2/2002 | Weber-Grabau et al. | | | |

EXAMINER: *[Signature]*

DATE CONSIDERED: *7/28/04*

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the patent owner.